



INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>		Docket Number (Optional) TWI-8520		Application Number 10/717,316	
		Applicant(s) Allan Rosencwaig et al.			
		Filing Date November 19, 2003	Group Art Unit 2877		

U.S. PATENT DOCUMENTS

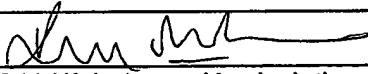
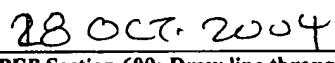
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
AM	BA	WO 95/00681	01/05/1995	PCT	C23G	1/00		
AM	BB	10-137704	11/08/1996	Japan (see Dialog Abstract in IDS text)	B08B	3/12		
AM	BC	WO 98/05066	02/05/1998	PCT	H01L	21/66		
AM	BD	WO 99/35677	07/15/1999	PCT	H01L	21/306		
AM	BE	4-357836	12/10/1999	Japan	H01L	21/304	Translation	

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

AM	BF	K. Imen et al., "Laser-assisted micron scale particle removal," <i>App. Phys. Lett.</i> , Vol. 58, No. 2, 14 January 1991, pp. 203-205.

Examiner 	Date Considered 
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	